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Applicant: David A. Palsulich et al.

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Title: MICROFEATURE WORKPIECE PROCESSING SYSTEM FOR, E.G., SEMICONDUCTOR WAFER ANALYSIS

Commissioner for Patents  
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Respectfully submitted,

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CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner of Patents and Trademarks, P.O. Box 1450, Alexandria VA 22313-1450, on this 13 day of August 2010.

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